PA-IDC

QUERY CONTROL FORM		RTIS USE ONLY	
Application No. 10/066,182	Prepared by J. Robbins	Tracking Number 05895837	
Examiner-GAU Phan-2818	Date 3-30-04	Week Date 1-26-04	
	No. of queries ①	IFW	

JACKET

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION

a. Page Missing

b. Text Continuity

c. Holes through Data

d. Other Missing Text

e. Illegible Text

f. Duplicate Text

g. Brief Description

h. Sequence Listing

i. Appendix

j. Amendments

k. Other

CLAIMS

a. Claim(s) Missing

(b. Improper Dependency)

c. Duplicate Numbers

d. Incorrect Numbering

e. Index Disagrees

f. Punctuation

g. Amendments

h. Bracketing

i. Missing Text

j. Duplicate Text

k. Other

MESSAGE Patent claim 30 (original claim 41) depends on canceled original claim 16; Patent claims 32-36 (original claims 43-47) depend on patent claim 39 (original claim 37). See claims in amendment indexed in IFW dated 11-25-2003.

Thank You

initials

RESPONSE DONE

initials TP

E-5 (Rev. 10/01/02)

Index of Claims

Application No. 10/066,182	**Applicant(s)** MCCLURE, DAVID C.	
Examiner TRONG PHAN	**Art Unit** 2818	

√	Rejected	—	(Through numeral) Cancelled	N	Non-Elected	
=	Allowed	+	Restricted	I	Interference	

A	Appeal	O	Objected		

Final	Original	12/19/03	Final	Original	Final	Original
1	1	=		51		101
2	2	|		52		102
3	3	|		53		103
4	4	|		54		104
5	5	=		55		105
	6	-		56		106
	7	-		57		107
6	8	=		58		108
7	9	|		59		109
8	10	|		60		110
9	11	|		61		111
12	12	|		62		112
13	13	|		63		113
14	14	|		64		114
15	15	=		65		115
	16	-		66		116
	17	|		67		117
	18	|		68		118
	19			69		119
	20			70		120
	21	-		71		121
16	22	=		72		122
17	23	|		73		123
18	24			74		124
19	25			75		125
20	26			76		126
21	27			77		127
22	28			78		128
23	29			79		129
24	30			80		130
25	31			81		131
26	32			82		132
27	33			83		133
28	34			84		134
29	35			85		135
30	36	|		86		136
32	37	=		87		137
	38	-		88		138
	39	-		89		139
10	40	=		90		140
11	41	|		91		141
31	42	|		92		142
33	43	|		93		143
34	44			94		144
35	45	|		95		145
36	46			96		146
37	47			97		147
38	48	|		98		148
39	49	=		99		149
	50			100		150

means for placing on an external pad of the apparatus during a test mode of operation a

current level corresponding to a voltage level appearing across the ferroelectric capacitor, <u>said</u>

<u>means</u> comprising a first transistor having a control terminal coupled to a plate of the

ferroelectric capacitor, a first conduction terminal coupled to the external pad and a second

conduction terminal ~~connected to a voltage reference~~, and a second transistor having a first

conduction terminal connected to ~~the external pad~~ <u>a voltage reference</u> and a second conduction

terminal connected to the ~~first~~ <u>second</u> conduction terminal of the first transistor, and a means for

selectively activating the second transistor during the test mode of operation.

38.   (Canceled).

39.   (Canceled).

40.   (Previously Added) The random access memory device of claim 1, wherein the

current level placed on the external pad by the test circuitry is proportional to the voltage level

appearing on the at least one bit line.

41.   (Previously Added) The method of claim 16, wherein the current level provided

to the pad is proportional to the voltage level appearing on the selected bit line.

42.   (Previously Added) The apparatus of claim 22, wherein the current level placed

on the external pad is proportional to the voltage level appearing on the at least one bit line.